

Form PTO-1449 COMMERCE (REV. 7-80)		U.S. DEPARTMENT OF PATENT AND TRADEMARK OFFICE		DOCKET NO. N1 000770		Serial No. 09/940819 NO 8/17/84									
				Applicant Rene Monshouwer et al		Group 2877 NO 8/17/84									
				Filing Date Concurrently											
INFORMATION DISCLOSURE CITATION (Use several sheets if necessary)															
U.S. PATENT DOCUMENTS															
Ex. Int.		Document Number							Date	Name	Class	Sub-class	Filing Date If Approp.		
120	AA	5	1	4	4	3	6	3	9/1/92	Wittekoek et al	355	53	1/24/91		
120	AB	4	5	4	0	2	7	7	9/10/85	Mayer et al	355	53	6/24/83		
120	AC	4	7	3	7	8	2	3	4/12/88	Bouwer et al	355	53	10/14/86		
120	AD	5	0	2	6	1	6	6	6/25/91	Van der Werf	356	401	10/1/84		
120	AE	5	1	9	1	2	0	0	3/2/93	Van der Werf	250	201	12/16/91		
120	AF	4	3	5	6	3	9	2	10/26/82	Wittekoek et al	250	201	6/11/80		
120	AG	4	8	6	1	1	6	2	8/29/89	Ina et al	356	401	11/15/88		
120	AH	5	4	1	4	5	1	4	5/9/95	Smith et al	356	363	6/1/93		
120	AI	4	7	7	8	2	7	5	10/18/88	Van den Brink	356	401	9/24/86		
120	AJ	4	2	5	1	1	6	0	2/17/81	Bouwuis et al	356	401	7/13/78		
120	AK	5	2	4	3	1	9	5	9/7/93	Nishi	250	548	12/29/92		
FOREIGN PATENT DOCUMENTS															
		Document Number							Date	Country	Class	Sub-Class	Trans.		
													Yes	No	
120	AL	0	4	9	8	4	9	9	8/12/92	Europe				X	
120	AM	9	8	3	9	6	8	9	9/11/98	World				X	
OTHER (Including Author, Title, Date, Pertinent Pages, Etc.)															
120	AN	"Submicrometer Lithographic Alignment and Overlay Strategies", by Saleem H. Zaidi et al, SPIE Vol. 1343, 1990, pages 245-255.													
120	AO	"Submicron 1:1 Optical Lighthography", by David A. Markle, Semiconductor International May 1986.													
Examiner <i>[Signature]</i>										Date Considered 8/17/84					

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